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Power system basis chip with high speed CAN and LIN transceivers

The 33907/33908 SMARTMOS devices are multi-output, power supply, integrated circuit, including HSCAN and/or LIN transceivers, dedicated to the automotive market.

Multiple switching and linear voltage regulators, including low-power mode (32 μ A) are available with various wake-up capabilities. An advanced power management scheme is implemented to maintain high efficiency over wide input voltages (down to 2.7 V) and wide output current ranges (up to 1.5 A).

The 33907/33908 include enhanced safety features, with multiple fail-safe outputs, becoming a full part of a safety oriented system partitioning, to reach a high integrity safety level (up to ASIL D).

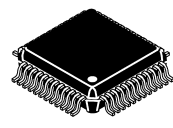
The built-in enhanced high-speed CAN interface fulfills the ISO11898-2 and -5 standards. The LIN interface fulfills LIN protocol specifications 1.3, 2.0, 2.1, 2.2, and SAEJ2602-2

Features

- Battery voltage sensing & MUX output pin
- Highly flexible SMPS pre-regulator, allowing two topologies: non-inverting buck-boost and standard buck
- Switching mode power supply (SMPS) dedicated to MCU core supply, from 1.2 V to 3.3 V delivering up to 1.5 A
- Multiple wake-up sources in low-power mode: CAN, LIN, and/or IOs
- Six configurable I/Os
- Linear voltage regulator dedicated to auxiliary functions, or to a sensor supply (V_{CCA} tracker or independent), 5.0 V or 3.3 V
- Linear voltage regulator dedicated to MCU A/D reference voltage or I/Os supply (V_{CCA}), 5.0 V or 3.3 V

33907 33908

POWER SYSTEM BASIS CHIP



**AE SUFFIX (PB-FREE)
98ASA00173D
48-PIN LQFP-EP**

Applications

- Electrical power steering
- Engine management
- Battery management
- Active suspension
- Gear box
- Transmission
- Electrical vehicle (EV), hybrid electrical vehicle (HEV), and inverter
- Advanced driver assistance systems

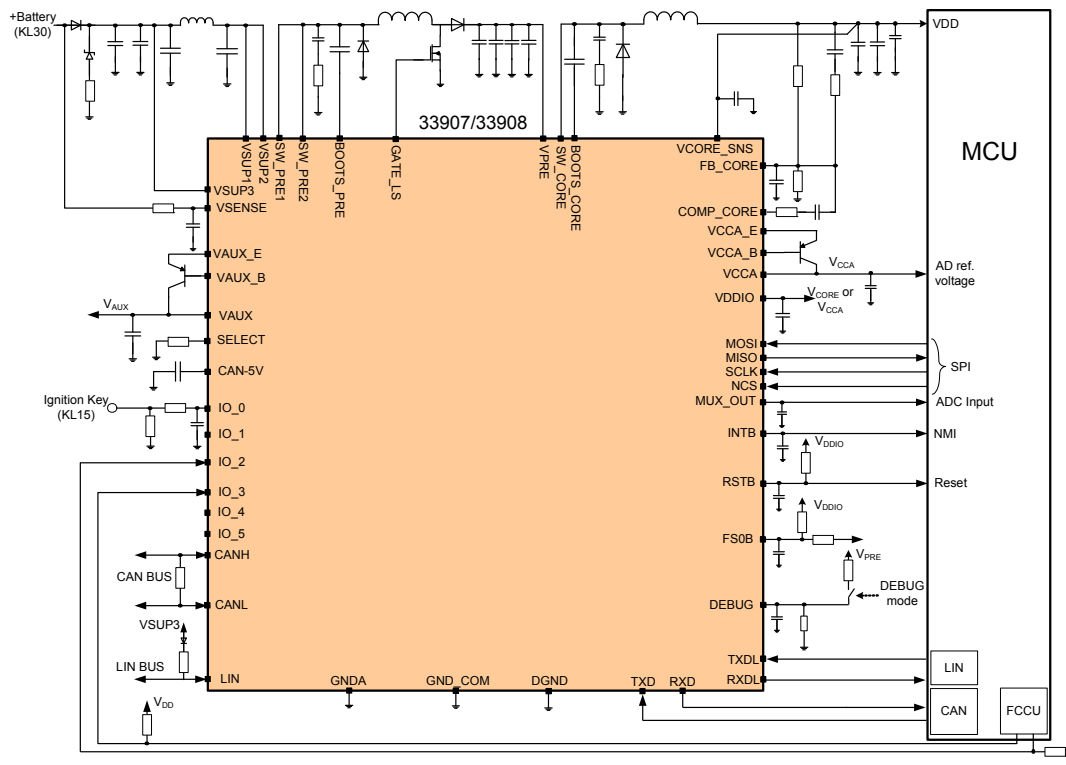


Figure 1. 33907/33908 simplified application diagram - buck boost configuration

* This document contains certain information on a new product. Specifications and information herein are subject to change without notice.



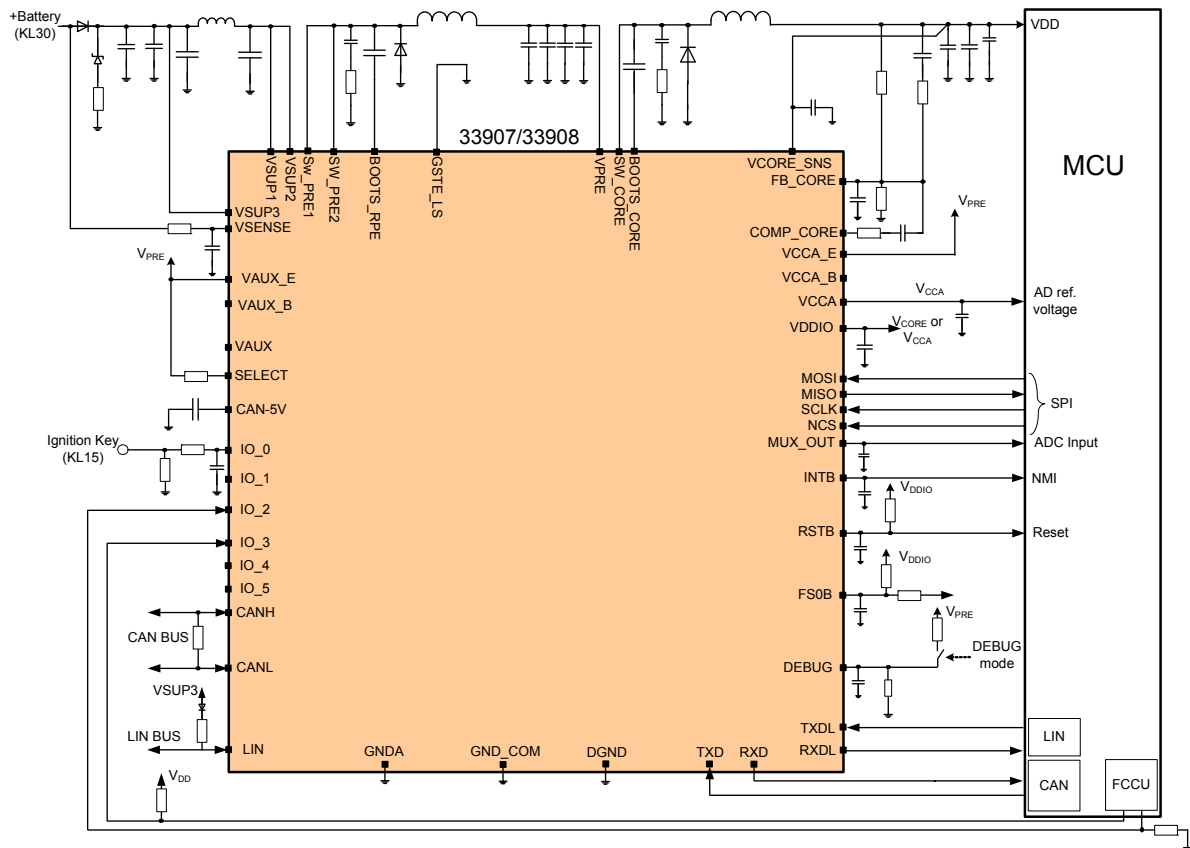


Figure 2. Simplified application diagram - buck configuration, V_{AUX} not used, $V_{CCA} = 100 \text{ mA}$

1 Orderable parts

Table 1. Orderable part variations

Part number	Temperature (T _A)	Package	CAN	LIN	V _{CORE}	Notes
MC33907NAE	-40 to 125 °C	48-pin LQFP exposed pad	1	0	0.8 A	(1)
MC33908NAE				0	1.5 A	
MC33907LAE				1	0.8 A	
MC33908LAE				1	1.5 A	

Notes

1. To order parts in Tape & Reel, add the R2 suffix to the part number.

2 Internal Block Diagram

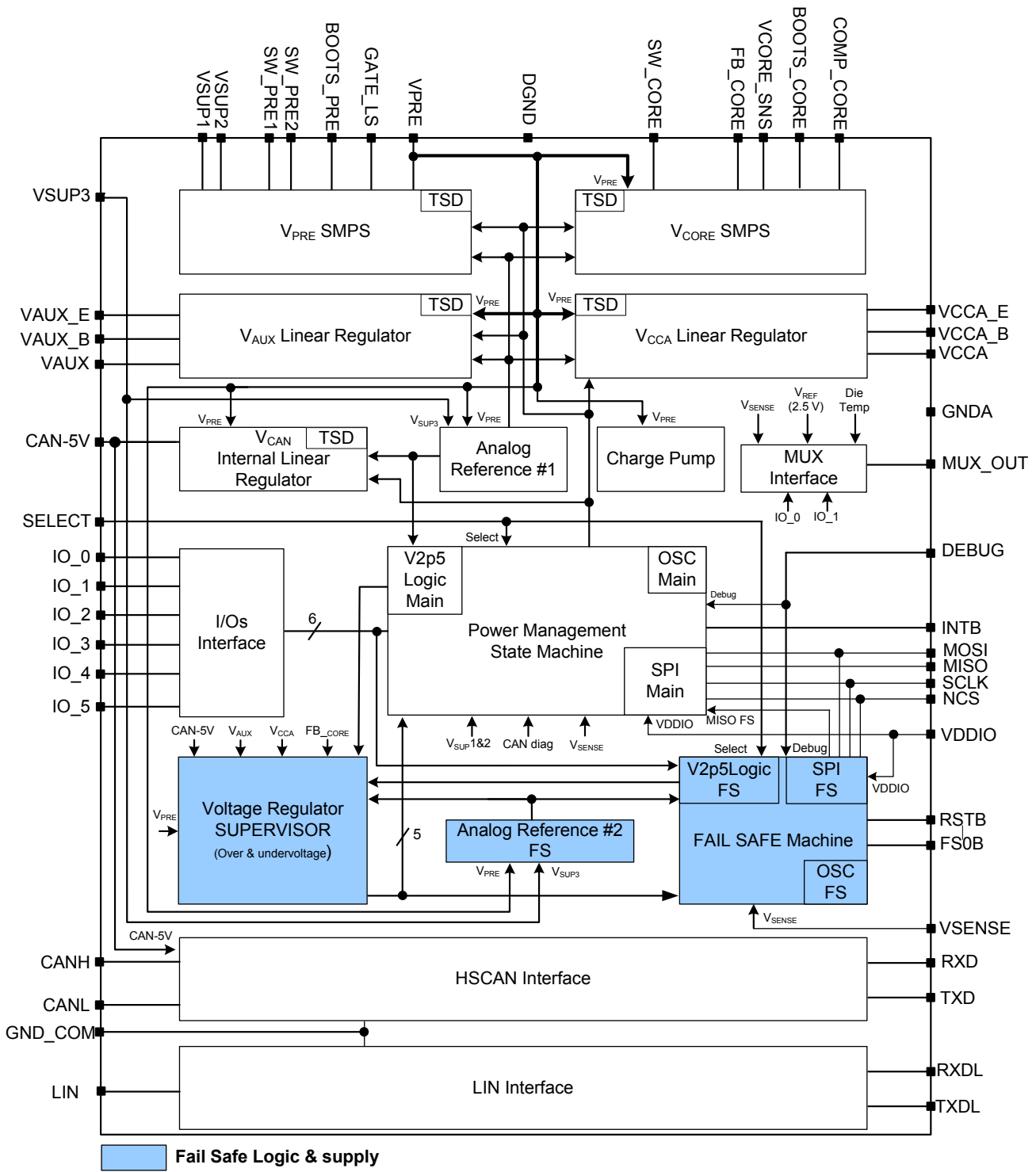


Figure 3. 33907L/33908L with CAN and LIN simplified internal block diagram

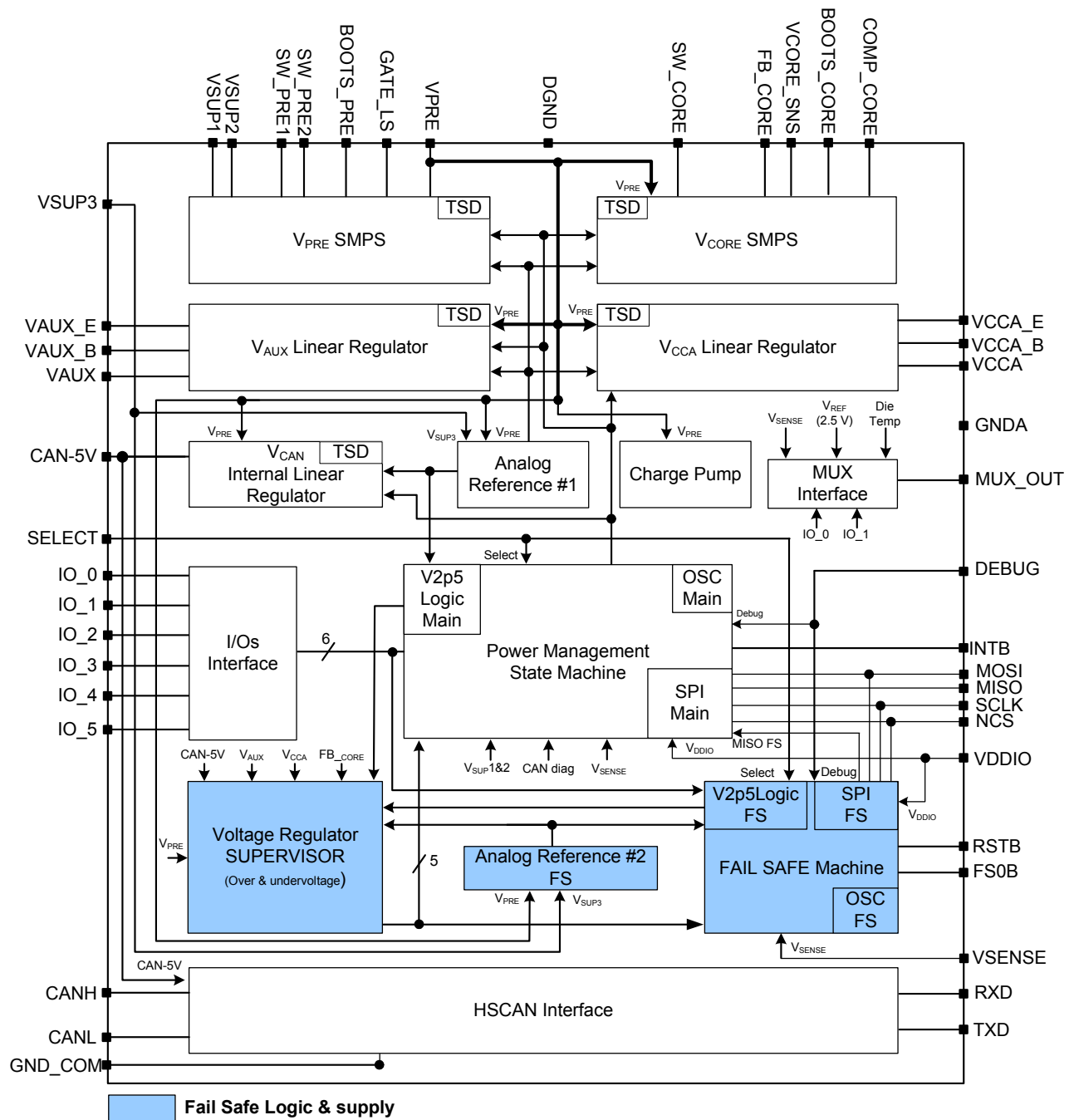


Figure 4. 33907N/33908N with CAN only simplified internal block diagram

3 Pin connections

3.1 Pinout diagram for 33907/33908

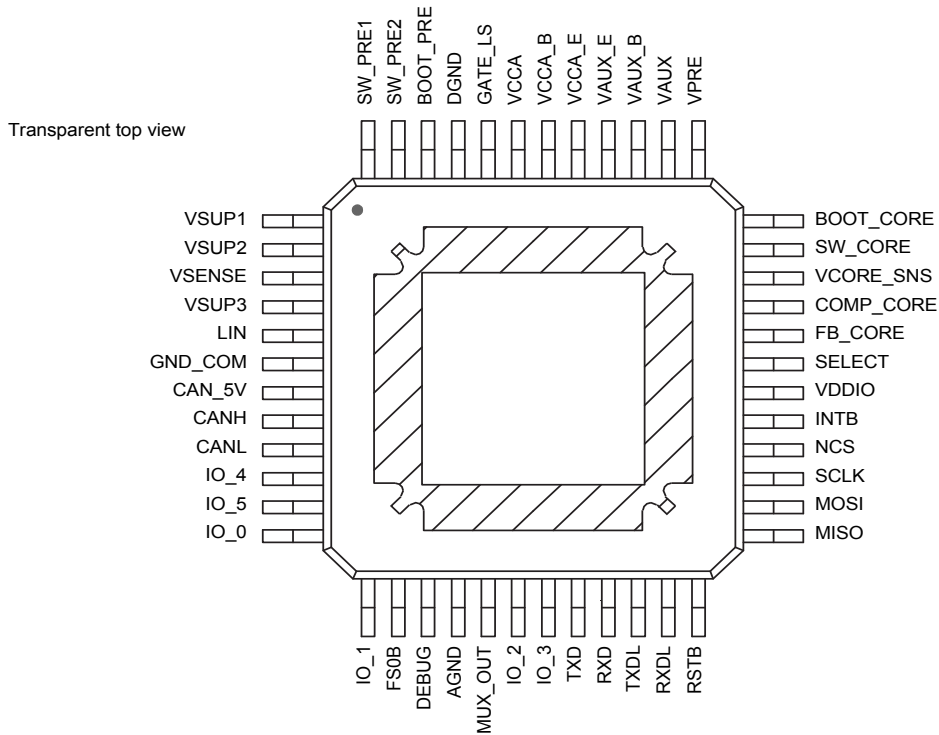


Figure 5. 33907L/33908L pinout with CAN and LIN

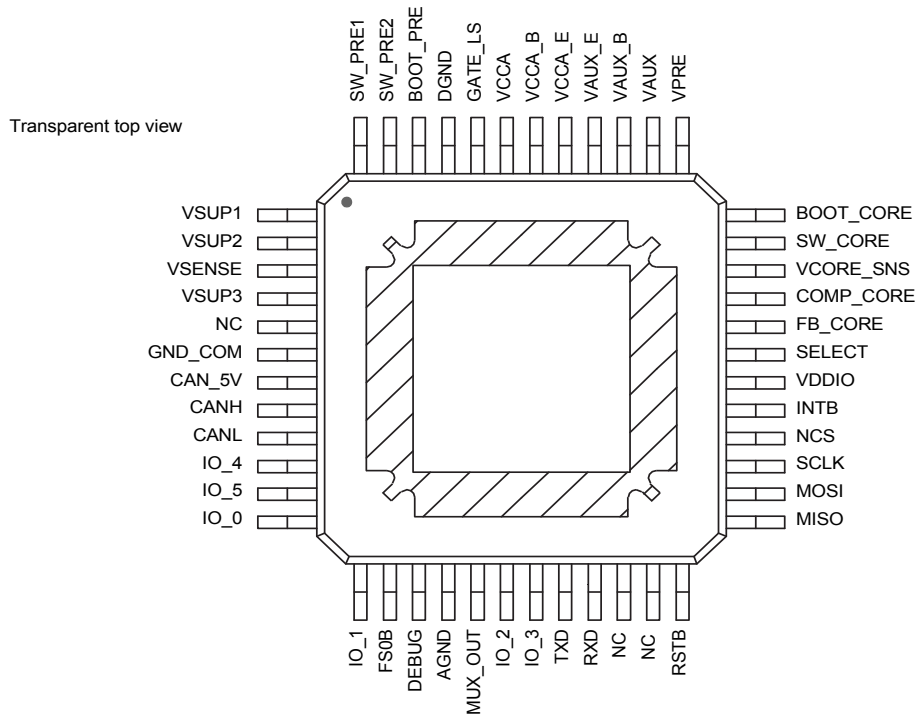


Figure 6. 33907N/33908N pinout with CAN only

3.2 Pin definitions

A functional description of each pin can be found in the functional pin description section beginning on [page 26](#).

Table 2. 33907/33908 pin definition

33907L/ 33908L pin number	33907N/ 33908N pin number	Pin name	Type	Definition
1	1	VSUP1	A_IN	Power supply of the device. An external reverse battery protection diode in series is mandatory
2	2	VSUP2	A_IN	Second power supply. Protected by the external reverse battery protection diode used for VSUP1. VSUP1 and VSUP2 must be connected together externally.
3	3	VSENSE	A_IN	Sensing of the battery voltage. Must be connected prior to the reverse battery protection diode.
4	4	VSUP3	A_IN	Third power supply dedicated to the device supply. Protected by the external reverse battery protection diode used for VSUP1. Must be connected between the reverse protection diode and the input PI filter.
5	NC	LIN	A_IN/OUT	LIN single-wire bus transmitter and receiver. NC: pin must be left open for 33907N/33908N version
6	6	GND_COM	GND	Dedicated ground for CAN
7	7	CAN_5V	A_OUT	Output voltage for the embedded CAN interface
8	8	CANH	A_IN/OUT	HSCAN output High
9	9	CANL	A_IN/OUT	HSCAN output Low
10 11	10 11	IO_4:5	D_IN A_OUT	Can be used as digital input (load dump proof) with wake-up capability or as an output gate driver Digital input: Pin status can be read through the SPI. Can be used to monitor error signals from another IC for safety purposes. Wake-up capability: Can be selectable to wake-up on a rising or falling edge, or on a transition Output gate driver: Can drive a logic level low-side NMOS transistor. Controlled by the SPI.
12 13	12 13	IO_0:1	A_IN D_IN	Can be used as analog or digital input (load dump proof) with wake-up capability (selectable) Analog input: Pin status can be read through the MUX output pin Digital input: Pin status can be read through the SPI. Can be used to monitor error signals from another IC for safety purposes Wake-up capability: Can be selectable to wake-up on a rising or falling edge, or on a transition Rk: For safety purposes, IO_1 can also be used to monitor the middle point of a redundant resistor bridge connected on Vcore (in parallel to the one used to set the Vcore voltage).
14	14	FS0B	D_OUT	Output of the safety block (active low). The pin is asserted low at start-up and when a fault condition is detected. Open drain structure.
15	15	DEBUG	D_IN	Debug mode entry input
16	16	AGND	GROUND	Analog ground connection
17	17	MUX_OUT	A_OUT	Multiplexed output to be connected to an MCU ADC input. Selection of the analog parameter is available at MUX-OUT through the SPI.
18 19	18 19	IO_2:3	D_IN	Digital input pin with wake-up capability (logic level compatible) Digital INPUT: Pin status can be read through the SPI. Can be used to monitor error signals from MCU for safety purposes. Wake-up capability: Can be selectable to wake-up on a rising or falling edge, or on a transition.
20	20	TXD	D_IN	Transceiver input from the MCU which controls the state of the HSCAN bus. Internal pull-up to VDDIO. Internal pull-up to VDDIO.
21	21	RXD	D_OUT	Receiver output which reports the state of the HSCAN bus to the MCU
22	NC	TXDL	D_IN	Transceiver input from the MCU which controls the state of the LIN bus. Internal pull-up to VDDIO. NC: pin must be left open for 33907N/33908N version

Table 2. 33907/33908 pin definition (continued)

33907L/ 33908L pin number	33907N/ 33908N pin number	Pin name	Type	Definition
23	NC	RXDL	D_OUT	Receiver output which reports the state of the LIN bus to the MCU. NC: pin must be left open for 33907N/33908N version
24	24	RSTB	D_OUT	This output is asserted low when the safety block reports a failure. The main function is to reset the MCU. Reset input voltage is also monitored in order to detect external reset and fault condition. Open drain structure.
25	25	MISO	D_OUT	SPI bus. Master Input Slave Output
26	26	MOSI	D_IN	SPI bus. Master Output Slave Input
27	27	SCLK	D_IN	SPI Bus. Serial clock
28	28	NCS	D_IN	No Chip Select (Active low)
29	29	INTB	D_OUT	This output pin generates a low pulse when an Interrupt condition occurs. Pulse duration is configurable. Internal pull-up to VDDIO.
30	30	VDDIO	A_IN	Input voltage for MISO output buffer. Allows voltage compatibility with MCU I/Os.
31	31	SELECT	D_IN	Hardware selection pin for VAUX and VCCA output voltages
32	32	FB_CORE	A_IN	VCORE voltage feedback. Input of the error amplifier.
33	33	COMP_CORE	A_IN	Compensation network. Output of the error amplifier.
34	34	VCORE_SNS	A_IN	VCORE output voltage sense
35	35	SW_CORE	A_IN	VCORE switching point
36	36	BOOT_CORE	A_IN/OUT	Bootstrap capacitor for VCORE internal NMOS gate drive
37	37	VPRE	A_OUT	VPRE output voltage
38	38	VAUX	A_OUT	VAUX output voltage. External PNP ballast transistor. Collector connection
39	39	VAUX_B	A_OUT	VAUX voltage regulator. External PNP ballast transistor. Base connection
40	40	VAUX_E	A_OUT	VAUX voltage regulator. External PNP ballast transistor. Emitter connection
41	41	VCCA_E	A_OUT	VCCA voltage regulator. External PNP ballast transistor. Emitter connection
42	42	VCCA_B	A_OUT	VCCA voltage regulator. External PNP ballast transistor. Base connection
43	43	VCCA	A_OUT	VCCA output voltage. External PNP ballast transistor. Collector connection
44	44	GATE_LS	A_OUT	Low-side MOSFET gate drive for "Non-inverting Buck-boost" configuration
45	45	DGND	GROUND	Digital ground connection
46	46	BOOT_PRE	A_IN/OUT	Bootstrap capacitor for the VPRE internal NMOS gate drive
47	47	SW_PRE2	A_IN	Second pre-regulator switching point
48	48	SW_PRE1	A_IN	First pre-regulator switching point

4 General product characteristics

4.1 Maximum ratings

Table 3. Maximum ratings

All voltages are with respect to ground, unless otherwise specified. Exceeding these ratings may cause a malfunction or permanent damage to the device.

Symbol	Ratings	Value	Unit	Notes
Electrical ratings				
V _{SUP1/2/3}	DC Voltage at Power Supply Pins	-1.0 to 40	V	(2)
V _{SENSE}	DC Voltage at Battery Sense Pin	-14 to 40	V	
V _{SW1,2}	DC Voltage at SW_PRE1 and SW_PRE2 Pins	-1.0 to 40	V	
V _{PRE}	DC Voltage at VPRE Pin	-0.3 to 8	V	
V _{GATE_LS}	DC Voltage at Gate_LS pin	-0.3 to 8	V	
V _{BOOT_PRE}	DC Voltage at BOOT_PRE pin	-1.0 to 50	V	
V _{SW_CORE}	DC Voltage at SW_CORE pin	-1.0 to 8.0	V	
V _{CORE_SNS}	DC Voltage at V _{CORE_SNS} pin	0.0 to 8.0	V	
V _{BOOT_CORE}	DC Voltage at BOOT_CORE pin	0.0 to 15	V	
V _{FB_CORE}	DC Voltage at FB_CORE pin	-0.3 to 2.5	V	
V _{COMP_CORE}	DC Voltage at COMP_CORE pin	-0.3 to 2.5	V	
V _{AUX_E,B}	DC Voltage at VAUX_E, VAUX_B pin	-0.3 to 40	V	
V _{AUX}	DC Voltage at VAUX pin	-2.0 to 40	V	
V _{VCCA_B,E}	DC Voltage at VCCA_B, VCCA_E pin	-0.3 to 8.0	V	
V _{VCCA}	DC Voltage at VCCA pin	-0.3 to 8.0	V	
V _{VDDIO}	DC Voltage at VDDIO	-0.3 to 8.0	V	
V _{FS0}	DC Voltage at FS0B (with ext R mandatory)	-0.3 to 40	V	
V _{DEBUG}	DC Voltage at DEBUG	-0.3 to 40	V	
V _{IO_0,1,4,5}	DC Voltage at IO_0:1; 4:5 (with ext R = 5.1 kΩ in series mandatory)	-0.3 to 40	V	
V _{DIG}	DC Voltage at INTB, RSTB, MISO, MOSI, NCS, SCLK, MUX_OUT, RXD, TXD, RXDL, TXDL, IO_2, IO_3	-0.3 to V _{VDDIO} +0.3	V	
V _{SELECT}	DC Voltage at SELECT	-0.3 to 8.0	V	
V _{BUS_CAN}	DC Voltage on CANL, CANH	-27 to 40	V	
V _{BUS_LIN}	DC Voltage on LIN	-18 to 40V	V	
V _{CAN_5V}	DC Voltage on CAN_5 V	-0.3 to 8.0	V	
I _{IO_0, 1, 4, 5}	IOs Maximum Current Capability(IO_0, IO_1, IO_4, IO_5)	-5.0 to 5.0	mA	

Notes

- All Vsups (V_{SUP1/2/3}) shall be connected to the same supply ([Figure 58](#))

Table 3. Maximum ratings (continued)

All voltages are with respect to ground, unless otherwise specified. Exceeding these ratings may cause a malfunction or permanent damage to the device.

Symbol	Ratings	Value	Unit	Notes
	ESD Voltage			
	Human Body Model (JESD22/A114) - 100 pF, 1.5 k Ω			
V _{ESD-HBM1}	• All pins	±2.0	kV	
V _{ESD-HBM2}	• VSUP1, VSUP2, VSUP3, VSENSE, VAUX, IO_0:1, IO_4:5, FS0B, DEBUG	±4.0	kV	
V _{ESD-HBM3}	• CANH, CANL	±6.0	kV	
V _{ESD-HBM4}	• LIN	±8.0	kV	
	Charge Device Model (JESD22/C101):			
V _{ESD-CDM1}	• All Pins	±500	V	
V _{ESD-CDM2}	• Corner Pins	±750	V	
	System level ESD (Gun Test)			
	• VSUP1, VSUP2, VSUP3, VSENSE, VAUX, IO_0:1, IO_4:5, FS0B			
V _{ESD-GUN1}	330 Ω / 150 pF Unpowered According to IEC61000-4-2:	±8.0	kV	
V _{ESD-GUN2}	330 Ω / 150 pF Unpowered According to OEM LIN, CAN, FLeXray Conformance	±8.0	kV	(3)
V _{ESD-GUN3}	2.0 k Ω / 150 pF Unpowered According to ISO10605.2008	±8.0	kV	
V _{ESD-GUN4}	2.0 k Ω / 330 pF Powered According to ISO10605.2008	±8.0	kV	
	• CANH, CANL			
V _{ESD-GUN5}	330 Ω / 150 pF Unpowered According to IEC61000-4-2:	±15.0	kV	
V _{ESD-GUN6}	330 Ω / 150 pF Unpowered According to OEM LIN, CAN, FLeXray Conformance	±12.0	kV	
V _{ESD-GUN7}	2.0 k Ω / 150 pF Unpowered According to ISO10605.2008	±15.0	kV	
V _{ESD-GUN8}	2.0 k Ω / 330 pF Powered According to ISO10605.2008	±15.0	kV	
	• LIN			
V _{ESD-GUN9}	330 Ω / 150 pF Unpowered According to IEC61000-4-2:	±15.0	kV	
V _{ESD-GUN10}	330 Ω / 150 pF Unpowered According to OEM LIN, CAN, FLeXray Conformance	±15.0	kV	
V _{ESD-GUN11}	2.0 k Ω / 150 pF Unpowered According to ISO10605.2008	±12.0	kV	
V _{ESD-GUN12}	2.0 k Ω / 330 pF Powered According to ISO10605.2008	±15.0	kV	

Thermal ratings

T _A	Ambient Temperature	-40 to 125	°C	
T _J	Junction Temperature	-40 to 150	°C	
T _{STG}	Storage Temperature	-55 to 150	°C	

Thermal resistance

R _{θJA}	Thermal Resistance Junction to Ambient	30	°C/W	(4)
R _{θJCTOP}	Thermal Resistance Junction to Case Top	24.2	°C/W	(5)
R _{θJCBOTTOM}	Thermal Resistance Junction to Case Bottom	0.9	°C/W	(6)

Notes

3. Compared to AGND.
4. Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC - 883 Method 1012.1).
6. Thermal resistance between the die and the solder par on the bottom of the packaged based on simulation without any interface resistance.

4.2 Static electrical characteristics

Table 4. Operating range

$T_{CASE} = -40\text{ °C}$ to 125 °C , unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V , unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
Power supply						
I_{SUP123}	Power Supply Current in Normal Mode ($V_{SUP} > V_{SUP_UV_7}$)	2.0	–	13.0	mA	
I_{SUP3}	Power Supply Current for VSUP3 in Normal Mode ($V_{SUP} > V_{SUP_UV_7}$)	–	3.5	5.0	mA	
I_{SUP_LPOFF1}	Power Supply Current in LPOFF ($V_{SUP} = 14\text{ V}$ at $T_A = 25\text{ °C}$)	–	32	–	μA	
I_{SUP_LPOFF2}	Power Supply Current in LPOFF ($V_{SUP} = 18\text{ V}$ at $T_A = 80\text{ °C}$)	–	42	60	μA	
V_{SNS_UV}	Power Supply Undervoltage Warning	–	8.5	–	V	
$V_{SNS_UV_HYST}$	Power Supply Undervoltage Warning Hysteresis	0.1	–	–	V	
$V_{SUP_UV_7}$	Power Supply Undervoltage Lockout (power-up)	7.0	–	8.0	V	
$V_{SUP_UV_5}$	Power Supply Undervoltage Lockout (power-up)	–	–	5.6	V	
$V_{SUP_UV_L}$	Power Supply Undervoltage Lockout (falling - Boost config.)	–	–	2.7	V	
$V_{SUP_UV_L_B}$	Power Supply Undervoltage Lockout (falling - Buck config.)	–	–	4.6	V	(7)
$V_{SUP_UV_HYST}$	Power Supply Undervoltage Lockout Hysteresis	–	0.1	–	V	(8)

V_{PRE} voltage pre-regulator

V_{PRE}	V_{PRE} Output Voltage <ul style="list-style-type: none"> Buck mode ($V_{SUP} > V_{SUP_UV_7}$) Buck mode ($V_{SUP_UV_7} \geq V_{SUP} \geq 4.6\text{ V}$) Boost mode ($V_{SUP} \geq 2.7\text{ V}$) 	6.25 $V_{PRE_UV_4}$ P3 6.0	– $V_{SUP} - R_{DSON_PRE} \cdot I_{PRE}$ –	6.75 – 7.0	V	
I_{PRE}	V_{PRE} Maximum Output Current Capability <ul style="list-style-type: none"> Buck or Boost with $V_{SUP} > V_{SUP_UV_7}$ Buck with $V_{SUP_UV_7} \geq V_{SUP} \geq 4.6\text{ V}$ Boost with $V_{SUP_UV_7} \geq V_{SUP} \geq 6.0\text{ V}$ Boost with $6.0\text{ V} \geq V_{SUP} \geq 4.0\text{ V}$ Boost with $4.0\text{ V} \geq V_{SUP} \geq 2.7\text{ V}$ 	2.0 0.5 2.0 1.0 0.3	– 2.0 – – –	– – – – –	A	(8)
I_{PRE_LPOFF}	V_{PRE} Maximum Output Current Capability in LPOFF at low V_{SUP} voltage <ul style="list-style-type: none"> Buck with $V_{SUP_UV_7} \geq V_{SUP} \geq 4.6\text{ V}$ Boost with $V_{SUP_UV_7} \geq V_{SUP} \geq 6.0\text{ V}$ Boost with $6.0\text{ V} \geq V_{SUP} \geq 4.0\text{ V}$ Boost with $4.0\text{ V} \geq V_{SUP} \geq 2.7\text{ V}$ 	0.05 2.0 1.0 0.3	– – – –	– – – –	A	(8)
I_{PRE_LIM}	V_{PRE} Output Current Limitation with $V_{SUP} \leq 28\text{ V}$	3.5	–	–	A	
I_{PRE_OC}	V_{PRE} Overcurrent Detection Threshold (in buck mode only) with $V_{SUP} \leq 28\text{ V}$	5.0	–	–	A	
V_{PRE_UV}	V_{PRE} Undervoltage Detection Threshold (Falling)	5.5	–	6.0	V	

Notes

- $V_{SUP_UV_L_B} = V_{PRE_UV_4P3} + R_{DSON_PRE} \cdot I_{PRE}$
- Guaranteed by design

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
V_{PRE} voltage pre-regulator (continued)						
V _{PRE_UV_HYST}	V _{PRE} Undervoltage Hysteresis	0.05	–	0.15	V	(9)
V _{PRE_UV_4P3}	V _{PRE} Shut-off Threshold (Falling - buck and buck/boost)	4.2	–	4.5	V	
V _{PRE_UV_4P3_HYST}	V _{PRE} Shut-off Hysteresis	0.05	–	0.15	V	(9)
R _{DSON_PRE}	V _{PRE} Pass Transistor On Resistance with $V_{SUP} \leq 28\text{ V}$	–	–	200	mΩ	
L _{IR_VPRE}	V _{PRE} Line Regulation	–	20	–	mV	(9)
LOR _{VPRE_BUCK}	V _{PRE} Load Regulation for C _{OUT} = 57 μF • I _{PRE} from 50 mA to 2.0 A - Buck mode	–	100	–	mV	(9)
LOR _{VPRE_BOOST}	V _{PRE} Load Regulation for C _{OUT} = 57 μF • I _{PRE} from 50 mA to 2.0 A - Boost mode	–	500	–	mV	(9)
V _{PRE_LL_H} V _{PRE_LL_L}	V _{PRE} Pulse Skipping Thresholds	– –	200 180	– –	mV	
T _{WARN_PRE}	V _{PRE} Thermal Warning Threshold	–	125	–	°C	
T _{SD_PRE}	V _{PRE} Thermal Shutdown Threshold	160	–	–	°C	
T _{SD_PRE_HYST}	V _{PRE} Thermal Shutdown Hysteresis	–	10	–	°C	(9)
V _{SUP_IPFF}	I _{PF} Input Voltage Detection	18	–	24	V	
V _{SUP_IPFF_HYST}	I _{PF} Input Voltage Hysteresis	0.2	–	–	V	
I _{PRE_IPFF_PK}	I _{PF} High-side Peak Current Detection with $V_{SUP} \leq 28\text{ V}$	1.7	–	–	A	
V _{G_LS_OH}	LS Gate Driver High Output Voltage (I _{OUT} = 50 mA)	V _{PRE} ⁻¹	–	V _{PRE}	V	
V _{G_LS_OL}	LS Gate driver Low Level (I _{OUT} = 50 mA)	–	–	0.5	V	

V_{CORE} voltage regulator

V _{CORE_FB}	V _{CORE} Feedback Input Voltage	0.784	0.8	0.816	V	
I _{CORE}	V _{CORE} Output Current Capability in Normal Mode					
	• 33907N	–	–	0.8	A	
	• 33908N	–	–	1.5	A	
	• 33907L	–	–	0.8	A	
I _{CORE_LIM}	V _{CORE} Output Current Limitation					
	• 33907N	1	–	2	A	
	• 33908N	1.8	–	3.5	A	
	• 33907L	1	–	2	A	
I _{CORE_LIM}	• 33908L	1.8	–	3.5	A	
R _{DSON_CORE}	V _{CORE} Pass Transistor On Resistance	–	–	200	mΩ	

Notes

9. Guaranteed by design

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
V_{CORE} voltage regulator (continued)						
LOR _{V_{CORE}_1.2}	V _{CORE} Transient Load regulation - 1.2 V range	-60	–	60	mV	(10), (11)
LOR _{V_{CORE}_3.3}	V _{CORE} Transient Load regulation - 3.3 V range	-100	–	100	mV	(10), (11)
V _{CORE_LL_H} V _{CORE_LL_L}	V _{CORE} Pulse Skipping Thresholds	– –	180 160	– –	mV	
T _{WARN_CORE}	V _{CORE} Thermal Warning Threshold	–	125	–	°C	
T _{SD_CORE}	V _{CORE} Thermal Shutdown Threshold	160	–	–	°C	
T _{SD_CORE_HYST}	V _{CORE} Thermal Shutdown Hysteresis	–	10	–	°C	(10)

V_{CCA} voltage regulator

V _{CCA}	V _{CCA} Output Voltage <ul style="list-style-type: none"> • 5.0 V config. with Internal ballast at 100 mA • 5.0 V config with external ballast at 200 mA • 5.0 V config with external ballast at 300 mA • 3.3 V config with Internal ballast at 100 mA • 3.3 V config with external ballast at 200 mA • 3.3 V config with external ballast at 300 mA 	4.95 4.9 4.85 3.2505 3.234 3.201	5.0 5.0 5.0 3.3 3.3 3.3	5.05 5.1 5.15 3.3495 3.366 3.399	V	(12)
I _{CCA_IN}	V _{CCA} Output Current (int. MOSFET)	–	–	100	mA	
I _{CCA_OUT}	V _{CCA} Output Current (external PNP)	–	–	300	mA	
I _{CCA_LIM_INT}	V _{CCA} Output Current Limitation (int. MOSFET)	100	–	675	mA	
I _{CCA_LIM_OUT}	V _{CCA} Output Current Limitation (external PNP)	300	–	675	mA	
I _{CCA_LIM_FB}	V _{CCA} Output Current Limitation Foldback	80	–	200	mA	
V _{CCA_LIM_FB}	V _{CCA} Output Voltage Foldback Threshold	0.5	–	1.1	V	
V _{CCA_LIM_HYST}	V _{CCA} Output Voltage Foldback Hysteresis	0.03	–	0.3	V	
I _{CCA_BASE_SC} I _{CCA_BASE_SK}	V _{CCA} Base Current Capability	– 20	– –	30 –	mA	
T _{WARN_CCA}	V _{CCA} Thermal Warning Threshold (int. MOSFET only)	–	125	–	°C	
T _{SD_CCA}	V _{CCA} Thermal Shutdown Threshold (int. MOSFET only)	160	–	–	°C	
T _{SD_CCA_HYST}	V _{CCA} Thermal Shutdown Hysteresis	–	10	–	°C	(13)
LORT _{V_{CCA}}	V _{CCA} Transient Load Regulation <ul style="list-style-type: none"> • I_{CCA} = 10 mA to 100 mA (internal MOSFET) • I_{CCA} = 10 mA to 300 mA (external ballast) 	–	–	1.0	%	(13)

Notes

10. Guaranteed by design.
11. C_{OUT} = 40 μF, I_{CORE} = 10 mA to 1.5 A, dI_{CORE}/dt ≤ 2.0 A/μs
12. External PNP gain within 150 to 450
13. Guaranteed by design.

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
Vaux voltage regulator						
V_{AUX_5}	V_{AUX} Output Voltage (5.0 V configuration)	4.85	5.0	5.15	V	
V_{AUX_33}	V_{AUX} Output Voltage (3.3 V configuration)	3.2	3.3	3.4	V	
V_{AUX_TRK}	V_{AUX} Tracking Error (V_{AUX_5} and V_{AUX_33})	-15	–	+15	mV	
I_{AUX_OUT}	V_{AUX} Output Current	–	–	300	mA	
I_{AUX_LIM}	V_{AUX} Output Current Limitation	300	–	700	mA	
$I_{AUX_LIM_FB}$	V_{AUX} Output Current Limitation Foldback	100	–	530	mA	
$V_{AUX_LIM_FB}$	V_{AUX} Output Voltage Foldback Threshold	0.5	–	1.1	V	
$V_{AUX_LIM_HYST}$	V_{AUX} Output Voltage Foldback Hysteresis	0.03	–	0.3	V	
$I_{AUX_BASE_SC}$ $I_{AUX_BASE_SK}$	V_{AUX} Base Current Capability	– 7.0	– –	-7.0 –	mA	
TSD_{AUX}	V_{AUX} Thermal Shutdown Threshold	160	–	–	$^{\circ}\text{C}$	
TSD_{AUX_HYST}	V_{AUX} Thermal Shutdown Hysteresis	–	10	–	$^{\circ}\text{C}$	(14)
LOR_{VAUX}	V_{AUX} Static Load Regulation ($I_{AUX_OUT} = 10\text{ mA}$ to 300 mA)	–	15	–	mV	(14)
$LORT_{VAUX}$	V_{AUX} Transient Load Regulation • $I_{AUX_OUT} = 10\text{ mA}$ to 300 mA	–	–	1.0	%	(14)

CAN_5V voltage regulator

V_{CAN}	V_{CAN} Output Voltage $V_{SUP} > 6.0\text{ V}$ in Buck mode $V_{SUP} > V_{SUP_UV_L}$ in Boost mode	4.8	5.0	5.2	V	
I_{CAN_OUT}	V_{CAN} Output Current	–	–	100	mA	
I_{CAN_LIM}	V_{CAN} Output Current Limitation	100	–	250	mA	
TSD_{CAN}	V_{CAN} Thermal Shutdown Threshold	160	–	–	$^{\circ}\text{C}$	
TSD_{CAN_HYST}	V_{CAN} Thermal Shutdown Hysteresis	–	10	–	$^{\circ}\text{C}$	(14)
V_{CAN_UV}	V_{CAN} Undervoltage Detection Threshold	4.25	–	4.8	V	
$V_{CAN_UV_HYST}$	V_{CAN} Undervoltage Hysteresis	0.07	–	0.22	V	
V_{CAN_OV}	V_{CAN} Overvoltage Detection Threshold	5.2	–	5.55	V	
$V_{CAN_OV_HYST}$	V_{CAN} Overvoltage Hysteresis	0.07	–	0.22	V	
LOR_{VCAN}	V_{CAN} Load Regulation (from 0 to 50 mA)	–	100	–	mV	(14)

Notes

14. Guaranteed by design.

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
Fail-safe machine voltage supervisor						
V_{PRE_OV}	V_{PRE} Overvoltage Detection Threshold	7.2	–	8.0	V	
$V_{PRE_OV_HYST}$	V_{PRE} Overvoltage Hysteresis	–	0.1	–	V	(15)
$V_{CORE_FB_UV}$	V_{CORE} FB Undervoltage Detection Threshold	0.67	–	0.773	V	
$V_{CORE_FB_UV_D}$	V_{CORE} FB Undervoltage Detection Threshold - Degraded mode	0.45	–	0.58	V	
$V_{CORE_FB_UV_HYST}$	V_{CORE} FB Undervoltage Hysteresis	10	–	27	mV	(15)
$V_{CORE_FB_OV}$	V_{CORE} FB Overvoltage Detection Threshold	0.84	–	0.905	V	
$V_{CORE_FB_OV_HYS_T}$	V_{CORE} FB Overvoltage Hysteresis	10	–	30	mV	(15)
$V_{CORE_FB_DRIFT}$	V_{CORE_FB} Drift versus IO_1	50	100	150	mV	
I_{PD_CORE}	V_{CORE} Internal Pull-down Current (active when V_{CORE} is enabled)	5.0	12	25	mA	
$V_{CCA_UV_5}$	V_{CCA} Undervoltage Detection Threshold (5.0 V config)	4.5	–	4.75	V	
$V_{CCA_UV_5D}$	V_{CCA} Undervoltage Detection Threshold (Degraded 5.0 V)	3.0	–	3.2	V	
$V_{CCA_UV_33}$	V_{CCA} Undervoltage Detection Threshold (3.3 V config)	3.0	–	3.2	V	
$V_{CCA_UV_HYST}$	V_{CCA} Undervoltage Hysteresis	–	0.07	–	V	(15)
$V_{CCA_OV_5}$	V_{CCA} Overvoltage Detection Threshold (5.0 V config)	5.25	–	5.5	V	
$V_{CCA_OV_33}$	V_{CCA} Overvoltage Detection Threshold (3.3 V config)	3.4	–	3.6	V	
$V_{CCA_OV_HYST}$	V_{CCA} Overvoltage Hysteresis	–	0.15	–	V	(15)
R_{PD_CCA}	V_{CCA} Internal Pull-down Resistor (active when V_{CCA} is disabled)	50	–	160	Ω	
$V_{AUX_UV_5}$	V_{AUX} Undervoltage Detection Threshold (5.0 V config)	4.5	–	4.75	V	
$V_{AUX_UV_5D}$	V_{AUX} Undervoltage Detection Threshold (Degraded 5.0 V)	3.0	–	3.2	V	
$V_{AUX_UV_33}$	V_{AUX} Undervoltage Detection Threshold (3.3 V config)	3.0	–	3.2	V	
$V_{AUX_UV_HYST}$	V_{AUX} Undervoltage Hysteresis	–	0.07	–	V	(15)
$V_{AUX_OV_5}$	V_{AUX} Overvoltage Detection Threshold (5.0 V config)	5.25	–	5.5	V	
$V_{AUX_OV_33}$	V_{AUX} Overvoltage Detection Threshold (3.3 V config)	3.4	–	3.6	V	
$V_{AUX_OV_HYST}$	V_{AUX} Overvoltage Hysteresis	–	0.07	–	V	(15)
R_{PD_AUX}	V_{AUX} Internal Pull-down Resistor (active when V_{AUX} is disabled)	50	–	170	Ω	

Notes

15. Guaranteed by design.

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
Fail-safe outputs						
V_{RSTB_OL}	Reset Low Output Level ($I_{RSTB} = 2.0\text{ mA}$ and $2.0\text{ V} < V_{SUP} < 40\text{ V}$)	–	–	0.5	V	(16)
I_{RSTB_LIM}	Reset Output Current Limitation	12	–	25	mA	
V_{RSTB_IL}	External Reset Detection Threshold (falling)	1.0	–	–	V	
V_{RSTB_IH}	External Reset Detection Threshold (rising)	–	–	2.0	V	
$V_{RSTB_IN_HYST}$	External Reset Input Hysteresis	0.2	–	–	V	
V_{FS0B_OL}	FS0B Low Output Level ($I_{FS0B} = 2.0\text{ mA}$)	–	–	0.5	V	
I_{FS0B_LK}	FS0B Input Current Leakage ($V_{FS0B} = 28\text{ V}$)	–	–	1.0	μA	
I_{FS0B_LIM}	FS0B Output Current Limitation	6.0	–	12	mA	

Analog input - multi-purpose IOs

$V_{IO_ANA_WD}$	Measurable Input Voltage (wide range)	3.0	–	19	V	
$V_{IO_ANA_TG}$	Measurable Input Voltage (tight range)	3.0	–	9.0	V	
$I_{IO_IN_ANA}$	Input Current	–	–	100	μA	

Digital input

V_{IO_IH}	Digital High Input voltage level (IO_0:1, IO_4:5) • Min Limit = 2.7 V at $V_{SUP} = 40\text{ V}$	2.6	–	–	V	
V_{IO23_IH}	Digital High Input voltage level (IO_2, IO_3)	2.0	–	–	V	
V_{IO_IL}	Digital Low Input voltage Level (IO_0:1; IO_4:5)	–	–	2.1	V	
V_{IO_HYST}	Input Voltage Hysteresis (IO_0:1, IO_4:5)	50	120	500	mV	(17)
V_{IO23_IL}	Digital Low Input voltage Level (IO_2, IO_3)	–	–	0.9	V	
V_{IO23_HYST}	Input Voltage Hysteresis (IO_2, IO_3)	200	450	700	mV	(17)
$I_{IO_IN_0:1}$	Input Current for IO_0:1	-5.0	–	100	μA	
$I_{IO_IN_1}$	Input Current for IO_1 when used for FB_Core monitoring	-1.0	–	1.0	μA	
$I_{IO_IN_2:5}$	Input Current for IO_2:5	-5.0	–	5.0	μA	
$I_{IO_IN_LPOFF}$	Input Current for IO_0:5 in LPOFF	-1.0	–	1.0	μA	

Output gate driver

V_{IO_OH}	High Output Level at $I_{IO_OUT} = -2.5\text{ mA}$	$V_{PRE} - 1.5$	–	V_{PRE}	V	
V_{IO_OL}	Low Output Level at $I_{IO_OUT} = +2.5\text{ mA}$	0.0	–	1.0	V	
$V_{IO_OUT_SK}$ $V_{IO_OUT_SC}$	Output Current Capability	2.5 –	– –	– -2.5	mA	

Notes

16. For $V_{SUP} < 2.0\text{ V}$, all supplies are already off and external pull-up on RSTB (e.g V_{CORE} or V_{CCA}) pulls the line down.
17. Guaranteed by design.

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
Analog multiplexer						
V_{AMUX_ACC}	Voltage Sense Accuracy (V_{SNS} , IO_0, IO_1) using 5.1 k Ω resistor	-5.0	–	5.0	%	(18)
$V_{AMUX_WD_5}$	Divider Ratio (wide input voltage range) at $V_{DDIO} = 5.0\text{ V}$	–	5.0	–		
$V_{AMUX_WD_3P3}$	Divider Ratio (wide input voltage range) at $V_{DDIO} = 3.3\text{ V}$	–	7.0	–		
$V_{AMUX_TG_5}$	Divider Ratio (tight input voltage range) at $V_{DDIO} = 5.0\text{ V}$	–	2.0	–		
$V_{AMUX_TG_3P3}$	Divider Ratio (tight input voltage range) at $V_{DDIO} = 3.3\text{ V}$	–	3.0	–		
V_{AMUX_REF1}	Internal Voltage Reference with $6.0\text{ V} < V_{SUP} < 19\text{ V}$	2.475	2.5	2.525	V	
V_{AMUX_REF2}	Internal Voltage Reference with $V_{SUP} \leq 6.0\text{ V}$ or $V_{SUP} \geq 19\text{ V}$	2.468	2.5	2.532	V	
$V_{AMUX_TP_CO}$	Internal Temperature sensor coefficient	–	9.9	–	mV/ $^{\circ}\text{C}$	(19)
V_{AMUX_TP}	Temperature Sensor MUX_OUT output voltage (at $T_J = 165^{\circ}\text{C}$)	2.08	2.15	2.22	V	
Interrupt						
V_{INTB_OL}	Low Output Level ($I_{INT} = 2.5\text{ mA}$)	–	–	0.5	V	
R_{PU_INT}	Internal Pull-up Resistor (connected to VDDIO)	–	10	–	K Ω	
I_{INT_LK}	Input Leakage Current	–	–	1	μA	
CAN transceiver						
CAN logic input pin (TXD)						
V_{TXD_IH}	TXD High Input Threshold	$0.7 \times V_{DDIO}$	–	–	V	
V_{TXD_IL}	TXD Low Input Threshold	–	–	$0.3 \times V_{DDIO}$	V	
TXD_{PULL_UP}	TXD Main Device Pull-up	20	33	50	K Ω	
TXD_{LK}	TXD Input Leakage Current, $V_{TXD} = V_{DDIO}$	-1.0	–	1.0	μA	
CAN logic output pin (RXD)						
V_{RXD_OL1}	Low Level Output Voltage ($I_{RXD} = 250\text{ }\mu\text{A}$)	–	–	0.4	V	
V_{RXD_OL2}	Low Level Output Voltage ($I_{RXD} = 1.5\text{ mA}$)	–	–	0.9	V	
V_{OUT_HIGH}	High Level Output Voltage ($I_{RXD} = -250\text{ }\mu\text{A}$, $V_{DDIO} = 3.0\text{ V}$ to 5.5 V)	$V_{DDIO} - 0.4\text{ V}$	–	–	V	

Notes

18. If a higher resistor value than recommended is used, the accuracy degrades.
19. Guaranteed by design

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
CAN output pins (CANH, CANL)						
$V_{DIFF_COM_MODE}$	Differential Input Comparator Common Mode Range	-12	–	12	V	
$V_{IN_DIFF_SLEEP}$	Differential Input Voltage Threshold in Sleep Mode	0.5	–	0.9	V	
V_{IN_HYST}	Differential Input Hysteresis (in TX, RX mode)	50	–	–	mV	
R_{IN_CHCL}	CANH, CANL Input Resistance	5.0	–	50	k Ω	
R_{IN_DIFF}	CAN Differential Input Resistance	10	–	100	k Ω	
R_{IN_MATCH}	Input Resistance Matching	-3.0	–	3.0	%	
V_{CANH}	CANH Output Voltage ($45\ \Omega < R_{BUS} < 65\ \Omega$) • TX dominant state • TX recessive state	2.75 2.0	– 2.5	4.5 3.0	V	
V_{CANL}	CANL Output Voltage ($45\ \Omega < R_{BUS} < 65\ \Omega$) • TX dominant state • TX recessive state	0.5 2.0	– 2.5	2.25 3.0	V	
V_{CAN_SYM}	CAN dominant voltage symmetry ($V_{CANL} + V_{CANH}$)	4.5	5	5.5	V	
$V_{OH} - V_{OL}$	Differential Output Voltage • TX dominant state ($45\ \Omega < R_{BUS} < 65\ \Omega$) • TX recessive state	1.5 -50	2.0 0.0	3.0 50	V mV	
I_{CANL_SK}	CANL Sink Current Under Short-circuit Condition ($V_{CANL} \leq 12\text{ V}$, CANL driver ON, TXD low)	40	–	100	mA	
I_{CANH_SC}	CANH Source Current Under Short-circuit Condition ($V_{CANH} = -2.0\text{ V}$, CANH driver ON, TXD low)	-100	–	-40	mA	
$R_{INSLEEP}$	CANH, CANL Input Resistance Device Supplied and in CAN Sleep Mode	5.0	–	50	k Ω	
V_{CANLP}	CANL, CANH Output Voltage in Sleep Modes. No termination load.	-0.1	0.0	0.1	V	
I_{CAN}	CANH, CANL Input Current, Device Unsupplied, ($V_{CANH}, V_{CANL} = 5.0\text{V}$) • V_{SUP} and V_{CAN} connected to GND • V_{SUP} and V_{CAN} connected to GND via 47k resistor	-10 -10	– –	10 10	μA μA	(20)
T_{OT}	Overtemperature Detection	160	–	–	$^{\circ}\text{C}$	
T_{HYST}	Overtemperature Hysteresis	–	–	20	$^{\circ}\text{C}$	

Digital interface

$MISO_H$	High Output Level on MISO ($I_{MISO} = 1.5\text{ mA}$)	$V_{DDIO} - 0.4$	–	–	V	
$MISO_L$	Low Output Level on MISO ($I_{MISO} = 2.0\text{ mA}$)	–	–	0.4	V	
I_{MISO}	Tri-state Leakage Current ($V_{DDIO} = 5.0\text{ V}$)	-5.0	–	5.0	μA	
V_{DDIO}	Supply Voltage for MISO Output Buffer	3.0	–	5.5	V	
$I_{V_{DDIO}}$	Current consumption on VDDIO	–	1.0	3.0	mA	
SPI_{LK}	SCLK, NCS, MOSI Input Current	-1.0	–	1.0	μA	
V_{SPI_IH}	SCLK, NCS, MOSI High Input Threshold	2.0	–	–	V	
R_{SPI}	NCS, MOSI Internal Pull-up (pull-up to VDDIO)	200	400	800	K Ω	
V_{SPI_IL}	SCLK, NCS, MOSI Low Input Threshold	–	–	0.8	V	

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
Debug						
V_{DEBUG_IL}	Low Input Voltage Threshold	2.1	2.35	2.6	V	
V_{DEBUG_IH}	High Input Voltage Threshold	4.35	4.6	4.97	V	
I_{DEBUG_LK}	Input Leakage Current	-10	–	10	μA	

LIN transceiver (when $7.0\text{ V} < V_{sup1,2,3} < 18\text{ V}$, unless otherwise specified) (33907L/33908L)

LIN logic input pin (TXDL)

V_{TXDL_IH}	TXDL High Input Threshold	2.0	–	–	V	
V_{TXDL_IL}	TXDL Low Input Threshold	–	–	0.8	V	
$TXDL_{PULL_UP}$	TXDL Internal Pull-up (to VDDIO)	20	33	50	$\text{k}\Omega$	
$TXDL_{LK}$	TXD Input Leakage Current, $V_{TXDL} = V_{DDIO}$	-1.0	–	1.0	μA	

LIN logic input pin (RXDL)

V_{RXDL_OL1}	Low Level Output Voltage ($I_{RXDL} = 250\text{ }\mu\text{A}$)	–	–	0.4	V	
V_{RXDL_OL2}	Low Level Output Voltage ($I_{RXDL} = 1.5\text{ mA}$)	–	–	0.9	V	
$V_{RXDL_OUT_HIGH}$	High Level Output Voltage ($I_{RXDL} = -250\text{ }\mu\text{A}$, $V_{DDIO} = 3.0\text{ V}$ to 5.5 V)	$V_{DDIO}-0.4\text{V}$	–	–	V	

LIN output pin

$I_{BUS_PAS_DOM}$	Input Leakage Current at the Receiver. Dominant State (Driver OFF, $V_{BAT} = 12\text{ V}$, $V_{BUS} = 0\text{ V}$)	-1.0	–	–	mA	(21)
$I_{BUS_PAS_REC}$	Input Leakage Current at the Receiver. Recessive State (Driver OFF, $8.0\text{ V} < V_{BAT} < 18\text{ V}$, $8.0\text{ V} < V_{BUS} < 18\text{ V}$, $V_{BUS} \geq V_{BAT}$)	–	–	20	μA	
V_{DRIVER_DOM}	Driver Dominant Voltage	–	–	$0.251 V_{SUP}$	V	
V_{BUS_DOM}	Receiver Dominant State	–	–	$0.4 V_{SUP}$	V	
V_{BUS_REC}	Receiver Recessive State	$0.6 V_{SUP}$	–	–	V	
V_{BUS_WU}	LIN Wake-up Detection Threshold ($7.0\text{ V} < V_{SUP} < 18\text{ V}$)	$0.4 V_{SUP}$	–	$0.6 V_{SUP}$	V	
V_{LIN_UV}	V_{SUP} Undervoltage Threshold	–	–	7.0	V	
V_{SER_DIODE}	Series Diode Voltage Drop (D_{SER_MASTER} and D_{SER_INT} in pull-up path)	0.4	0.7	1.0	V	
I_{BUS_LIM}	Current Limitation for Driver Dominant State ($V_{BUS} = 18\text{ V}$)	40	–	200	mA	(22)
R_{SLAVE}	LIN Pull-up Resistor	20	–	60	$\text{k}\Omega$	
V_{SHIFT_GND}	Ground Shift ($V_{SHIFT_GND} = V_{GND_ECU} - V_{GND_BATTERY}$)	0.0	–	$11.5\%V_{BAT}$	V	
V_{SHIFT_BAT}	Battery Voltage Shift ($V_{SHIFT_BAT} = V_{BATTERY} - V_{SHIFT_GND} - V_{BAT}$)	0.0	–	$11.5\%V_{BAT}$	V	(23)

Notes

- Guaranteed by design and characterization.
- V_{BAT} is the voltage at the input of the control unit.
- Current flowing inside the pin. A transceiver must be capable to sink at least 40 mA.
- V_{BAT} : voltage across the battery connectors of the vehicle. V_{GND_ECU} : voltage on the local ECU ground connector with respect to battery ground of the vehicle ($V_{GND_BATTERY}$).

Table 4. Operating range (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
LIN output pin (continued)						
V_{SHIFT_DIF}	Difference Between Battery Shift and Ground Shift ($V_{SHIFT_DIF} = V_{SHIFT_BAT} - V_{SHIFT_GND}$)	0.0	–	8.0% V_{BAT}	V	(24)
V_{BUS_CNT}	$V_{BUS_CNT} = (V_{TH_REC} + V_{TH_DOM})/2$	0.475 V_{SUP}	–	0.525 V_{SUP}	V	(25)
V_{HYST}	$V_{HYST} = V_{TH_REC} - V_{TH_DOM}$	–	–	0.175 V_{SUP}	V	
$I_{BUS_NO_GND}$	Ground Disconnection. $GND = V_{SUP}$, $0\text{ V} < V_{BUS} < 18\text{ V}$, $V_{BAT} = 12\text{ V}$. Loss of Local GND does not affect communication in the remaining network	-1.0	–	1.0	mA	(26)
$I_{BUS_NO_BAT}$	VBAT disconnection. $V_{SUP} = GND$, $0\text{ V} < V_{BUS} < 18\text{ V}$. Node sustains the current that can flow under this condition. BUS remains operational.	–	–	100	μA	
LIN_{TSD}	LIN Thermal Shutdown	–	180	–	$^{\circ}\text{C}$	(27)
LIN_{TSD_HYST}	LIN Thermal Shutdown Hysteresis	–	20	–	$^{\circ}\text{C}$	
C_{LIN}	LIN internal capacitor	–	–	10	pF	(27)

Notes

24. This constraint refers to duty cycle D1 and D2 only.
25. V_{TH_DOM} : receiver threshold of the recessive to dominant LIN bus edge. V_{TH_REC} receiver threshold of the dominant to recessive LIN bus edge.
26. V_{SUP} is the voltage at the input of the device (different from V_{bat} when a reverse current protection diode is implemented).
27. Guaranteed by design.

4.3 Dynamic electrical characteristics

Table 5. Dynamic electrical characteristics

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V , unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
f_{SPI}	SPI Operation Frequency (50% DC)	0.5	–	8.0	MHz	
t_{MISO_TRANS}	MISO Transition Speed, 20 - 80% • $V_{DDIO} = 5.0\text{ V}$, $C_{LOAD} = 50\text{ pF}$ • $V_{DDIO} = 5.0\text{ V}$, $C_{LOAD} = 150\text{ pF}$	5.0 5.0	– –	30 50	ns	
t_{CLH}	Minimum Time SCLK = HIGH	62	–	–	ns	
t_{CLL}	Minimum Time SCLK = LOW	62	–	–	ns	
t_{PCLD}	Propagation Delay (SCLK to data at 10% of MISO rising edge)	–	–	30	ns	
t_{CSDV}	NCS = LOW to Data at MISO Active	–	–	75	ns	
t_{SCLCH}	SCLK Low Before NCS Low (setup time SCLK to NCS change H/L)	75	–	–	ns	
t_{HCLCL}	SCLK Change L/H after NCS = low	75	–	–	ns	
t_{SCLD}	SDI Input Setup Time (SCLK change H/L after MOSI data valid)	40	–	–	ns	
t_{HCLD}	SDI Input Hold Time (MOSI data hold after SCLK change H/L)	40	–	–	ns	
t_{SCLCL}	SCLK Low Before NCS High	100	–	–	ns	
t_{HCLCH}	SCLK High After NCS High	100	–	–	ns	
t_{PCHD}	NCS L/H to MISO at High-impedance	–	–	75	ns	
t_{ONNCS}	NCS Min. High Time	500	–	–	ns	
t_{NCS_MIN}	NCS Filter Time	10	–	40	ns	

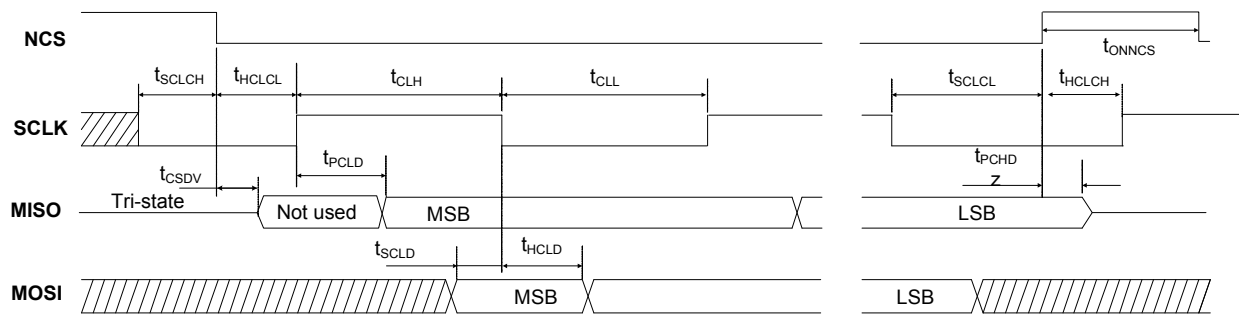


Figure 7. SPI timing diagram

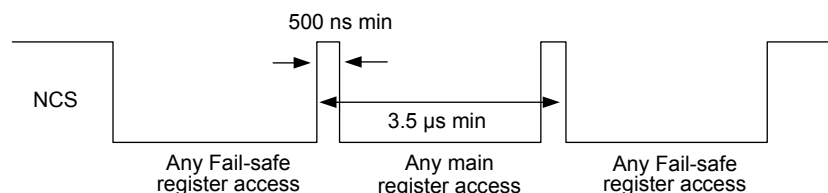


Figure 8. Register access restriction

Table 5. Dynamic electrical characteristics (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
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CAN dynamic characteristics

t_{DOUT}	TXD Dominant State Timeout	0.8	–	5.0	ms	
t_{DOM}	Bus Dominant Clamping Detection	0.8	–	5.0	ms	
t_{LOOP}	Propagation Loop Delay TXD to RXD • $R_{LOAD} = 120\ \Omega$, C between CANH and CANL = 100 pF, C at RxD < 15 pF	–	–	255	ns	
t_{1PWU}	Single Pulse Wake-up Time	0.5	–	5.0	μs	
t_{3PWU}	Multiple Pulse Wake-up Time	0.5	–	1.0	μs	
t_{3PTO1}	Multiple Pulse Wake-up Timeout (120 μs bit selection)	110	120	–	μs	
t_{3PTO2}	Multiple Pulse Wake-up Timeout (360 μs bit selection)	350	360	–	μs	
t_{CAN_READY}	Delay to Enable CAN by SPI Command (NCS rising edge) to CAN to Transmit (device in normal mode and CAN interface in TX/RX mode)	–	–	100	μs	(28)

Fail-safe state machine

OSC_{FSSM}	Oscillator	405	–	495	kHz	
CLK_{FS_MIN}	Fail-safe Oscillator Monitoring	150	–	–	kHz	
t_{IC_ERR}	IO_0:5 Filter Time	4.0	–	20	μs	
t_{ACK_FS}	Acknowledgement Counter (used for IC error handling IO_1 and IO_5)	7.0	–	9.7	ms	
$t_{DFS_RECOVERY}$	IO_0 Filter Time to Recover from Deep Reset and Fail State	0.8	–	1.3	ms	
$t_{IO1_DRIFT_MON}$	IO_1 filter time	1.0	–	2.0	ms	

Fail-safe output

t_{RSTB_FB}	RSTB Feedback Filter Time	8.0	–	15	μs	
t_{FSOB_FB}	FS0B Feedback Filter Time	8.0	–	15	μs	
t_{RSTB_BLK}	RSTB Feedback Blanking Time	180	–	320	μs	
t_{FSOB_BLK}	FS0B Feedback Blanking Time	180	–	320	μs	
t_{RSTB_POR}	Reset Delay Time (after a Power On Reset or from LPOFF)	12	15.9	23.6	ms	(29)
t_{RSTB_LG}	Reset Duration (long pulse)	8.0	–	10	ms	
t_{RSTB_ST}	Reset duration (short pulse)	1.0	–	1.3	ms	
t_{RSTB_IN}	External Reset Delay time	8.0	–	15	μs	
t_{DIAG_SC}	Fail-safe Output Diagnostic Counter (FS0B)	550	–	800	μs	

VSUP voltage supply

C_{SUP}	Minimum capacitor on Vsup	44	–	–	μF	
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Notes

28. For proper CAN operation, TXD must be set to high level before CAN enable by SPI, and must remain high for at least T_{CAN_READY} .
29. This timing is not guaranteed in case of fault during startup phase (after Power On Reset or from LPOFF)

Table 5. Dynamic electrical characteristics (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
V_{PRE} voltage pre-regulator						
f_{SW_PRE}	V _{PRE} Switching Frequency	418	440	462	kHz	
t_{SW_PRE}	V _{SW_PRE} On and Off Switching Time	–	–	30	ns	(30)
t_{PRE_SOFT}	V _{PRE} Soft Start Duration ($C_{OUT} \leq 100\text{ }\mu\text{F}$)	500	–	700	μs	
$t_{PRE_BLK_LIM}$	V _{PRE} Current Limitation Blanking Time	200	–	600	ns	
t_{PRE_OC}	V _{PRE} Overcurrent Filtering Time	30	–	120	ns	(30)
t_{PRE_UV}	V _{PRE} Undervoltage Filtering Time	20	–	40	μs	
$t_{PRE_UV_4p3}$	V _{PRE} Shut-off Filtering Time	3.0	–	6.0	μs	
$d_{IPRE/DT}$	V _{PRE} Load Regulation Variation	–	–	25	A/ms	(30)
t_{PRE_WARN}	V _{PRE} Thermal Warning Filtering Time	30	–	40	μs	
t_{PRE_TSD}	V _{PRE} Thermal Detection Filtering Time	1.3	–	–	μs	
t_{VSUP_IPFF}	I _{PFF} Input Voltage Filtering Time	1.0	–	5.0	μs	
t_{IPRE_IPFF}	I _{PFF} High-side Peak Current Filter Time	100	–	300	ns	
$t_{LS_RISE/FALL}$	LS Gate Voltage Switching Time ($I_{OUT} = 300\text{ mA}$)	–	–	50	ns	
V_{SENSE} voltage regulator						
t_{VSNS_UV}	V _{SNS} Undervoltage Filtering Time	1.0	–	3.0	μs	
V_{CORE} voltage regulator						
$t_{CORE_BLK_LIM}$	V _{CORE} Current Limitation Blanking Time	20	–	40	ns	
f_{SW_CORE}	V _{CORE} Switching Frequency	2.28	2.4	2.52	MHz	
t_{SW_CORE}	V _{SW_CORE} On and Off Switching Time	6.0	–	12	ns	
V_{CORE_SOFT}	V _{CORE} Soft Start ($C_{OUT} = 100\text{ }\mu\text{F}$ max)	–	–	10	V/ms	
t_{CORE_WARN}	V _{CORE} Thermal Warning Filtering Time	30	–	40	μs	
t_{CORE_TSD}	V _{CORE} Thermal Detection Filtering Time	0.5	–	–	μs	
V_{CCA} voltage regulator						
t_{CCA_LIM}	V _{CCA} Output Current Limitation Filter Time	1.0	–	3.0	μs	
$t_{CCA_LIM_OFF1}$ $t_{CCA_LIM_OFF2}$	V _{CCA} Output Current Limitation Duration	10 50	– –	– –	ms	
t_{CCA_WARN}	V _{CCA} Thermal Warning Filtering Time	30	–	40	μs	
t_{CCA_TSD}	V _{CCA} Thermal Detection Filter Time (int. MOSFET)	1.5	–	–	μs	
dI_{LOAD}/dt	V _{CCA} Load Transient	–	2.0	–	A/ms	(30)
V_{CCA_SOFT}	V _{CCA} Soft Start (5.0 V and 3.3 V)	–	–	50	V/ms	

Notes

30. Guaranteed by characterization.

Table 5. Dynamic electrical characteristics (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
V_{AUX} voltage regulator						
t_{AUX_LIM}	V_{AUX} Output Current Limitation Filter Time	1.0	–	3.0	μs	
$t_{AUX_LIM_OFF1}$ $t_{AUX_LIM_OFF2}$	V_{AUX} Output Current Limitation Duration	10 50	– –	– –	ms	
t_{AUX_TSD}	V_{AUX} Thermal Detection Filter Time	1.5	–	–	μs	
dI_{AUX}/dt	V_{AUX} Load Transient	–	2.0	–	A/ms	(31)
V_{AUX_SOFT}	V_{AUX} Soft Start (5.0 V and 3.3 V)	–	–	50	V/ms	
V_{CAN_5V} voltage regulator						
t_{CAN_LIM}	Output Current Limitation Filter Time	2.0	–	4.0	μs	
t_{CAN_TSD}	V_{CAN} Thermal Detection Filter Time	1.0	–	–	μs	
t_{CAN_UV}	V_{CAN} Undervoltage Filtering Time	4.0	–	7.0	μs	
t_{CAN_OV}	V_{CAN} Overvoltage Filtering Time	100	–	200	μs	
dI_{CAN}/dt	V_{CAN} Load Transient	–	100	–	A/ms	(31)
Fail-safe machine voltage supervisor						
t_{PRE_OV}	V_{PRE} Overvoltage Filtering Time	128	–	234	μs	
t_{CORE_UV}	V_{CORE} FB Undervoltage Filtering Time	4.0	–	10	μs	
t_{CORE_OV}	V_{CORE} FB Overvoltage Filtering Time	128	–	234	μs	
t_{CCA_UV}	V_{CCA} Undervoltage Filtering Time	4.0	–	10	μs	
t_{CCA_OV}	V_{CCA} Overvoltage Filtering Time	128	–	234	μs	
t_{AUX_UV}	V_{AUX} Undervoltage Filtering Time	4.0	–	10	μs	
t_{AUX_OV}	V_{AUX} Overvoltage Filtering Time	128	–	234	μs	
Digital input - multi-purpose ios						
F_{IO_IN}	Digital Input Frequency Range	0.0	–	100	kHz	
Analog multiplexer						
t_{MUX_READY}	SPI Selection to Data Ready to be Sampled on Mux_out • $V_{DDIO} = 5.0\text{ V}$, $C_{MUX_OUT} = 1.0\text{ nF}$	–	–	10	μs	
Interrupt						
t_{INTB_LG}	INTB Pulse Duration (long)	90	100	–	μs	
t_{INTB_ST}	INTB Pulse Duration (short)	20	25	–	μs	
Functional sate machine						
t_{WU_GEN}	General Wake-up Signal Deglitch Time (for any wu signal on IOs)	60	70	80	μs	

Notes

31. Guaranteed by characterization.

Table 5. Dynamic electrical characteristics (continued)

$T_{CASE} = -40\text{ }^{\circ}\text{C}$ to $125\text{ }^{\circ}\text{C}$, unless otherwise specified. $V_{SUP} = V_{SUP_UV_L}$ to 40 V, unless otherwise specified. All voltages referenced to ground. When $28\text{ V} < V_{SUP} < 40\text{ V}$, thermal dissipation must be considered (Figure 25).

Symbol	Parameter	Min.	Typ.	Max.	Unit	Notes
LIN dynamic characteristics (when 7.0 V < Vsup1, 2, 3 < 18 V, unless otherwise specified) (33907L/33908L)						
t_{RX_PD}	Receiver Propagation Delay ($T_{RX_PD} = \text{MAX}(t_{REC_PDR}, t_{REC_PDF})$)	–	–	6.0	μs	
t_{RX_SYM}	Symmetry of Receiver Propagation Delay ($T_{RX_SYM} = t_{REC_PDF} - t_{REC_PDR}$)	-2.0	–	2.0	μs	
t_{BUS_WU}	BUS Wake-up Filter Time	–	–	250	μs	
t_{XD_DOM}	TXD_L Permanent Dominant State Delay	–	5.0	–	ms	
$t_{LIN_SHORT_GND}$	LIN Short-circuit to GND Deglitcher	–	15	–	ms	
BD_{FAST}	Fast Baud Rate	–	–	100	KB/s	
D1	Duty Cycle D1 $TH_{REC}(\text{max}) = 0.744 \times V_{SUP}$, $TH_{DOM}(\text{max}) = 0.581 \times V_{SUP}$ V_{SUP} 7.0 V to 18 V, $t_{BIT} = 50\text{ }\mu\text{s}$ $D1 = t_{BUS-rec}(\text{min}) / (2t_{BIT})$	0.396	–	–	%	(32)
D2	Duty Cycle D2 $TH_{REC}(\text{min}) = 0.422 \times V_{SUP}$, $TH_{DOM}(\text{min}) = 0.284 \times V_{SUP}$ V_{SUP} 7.6 V to 18 V, $t_{BIT} = 50\text{ }\mu\text{s}$ $D2 = t_{BUS-rec}(\text{max}) / (2t_{BIT})$	–	–	0.581	%	(32)
D3	Duty Cycle D3 $TH_{REC}(\text{max}) = 0.778 \times V_{SUP}$, $TH_{DOM}(\text{max}) = 0.616 \times V_{SUP}$ V_{SUP} 7.0 V to 18 V, $t_{BIT} = 96\text{ }\mu\text{s}$ $D3 = t_{BUS-rec}(\text{min}) / (2t_{BIT})$	0.417	–	–	%	(32)
D4	Duty Cycle D4 $TH_{REC}(\text{min}) = 0.389 \times V_{SUP}$, $TH_{DOM}(\text{min}) = 0.251 \times V_{SUP}$ V_{SUP} 7.6 V to 18 V, $t_{BIT} = 96\text{ }\mu\text{s}$ $D4 = t_{BUS-rec}(\text{max}) / (2t_{BIT})$	–	–	0.59	%	(32)

Notes

32. LIN Driver, Bus load conditions (CBUS,RBUS): 1.0 nF;1.0 k Ω / 6.8 nF;660 Ω / 10 nF;500 Ω